# **IGBT**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss.

#### **Features**

- Low Saturation Voltage using Trench with Field Stop Technology
- Low Switching Loss Reduces System Power Dissipation
- Optimized for High Speed Switching
- 5 µs Short–Circuit Capability
- These are Pb-Free Devices

### **Typical Applications**

- Power Factor Correction
- Solar Inverters
- Uninterruptable Power Supply (UPS)

#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter voltage	V <sub>CES</sub>	600	V
Collector current @ Tc = 25°C @ Tc = 100°C	I <sub>C</sub>	60 30	A
Pulsed collector current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>CM</sub>	120	Α
Diode Forward Current @ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 100°C	I <sub>F</sub>	60 30	A
Diode Pulsed Current T <sub>pulse</sub> Limited by T <sub>Jmax</sub>	I <sub>FM</sub>	120	Α
Short–circuit withstand time $V_{GE} = 15 \text{ V}, V_{CE} = 300 \text{ V}, $ $T_J \le +150^{\circ}\text{C}$	t <sub>SC</sub>	5	μS
Gate-emitter voltage Transient Gate Emitter Voltage (t <sub>p</sub> = 5 μs, D < 0.010)	V <sub>GE</sub>	±20 ±30	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	250 67	W
Operating junction temperature range	TJ	–55 to +150	°C
Storage temperature range	T <sub>stg</sub>	-55 to +150	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

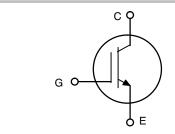
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

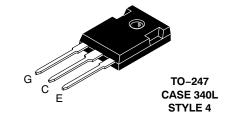


# ON Semiconductor®

http://onsemi.com

30 A, 600 V V<sub>CEsat</sub> = 1.65 V





### **MARKING DIAGRAM**



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

#### **ORDERING INFORMATION**

Device	Package	Shipping
NGTG30N60FLWG	TO-247 (Pb-Free)	30 Units / Rail

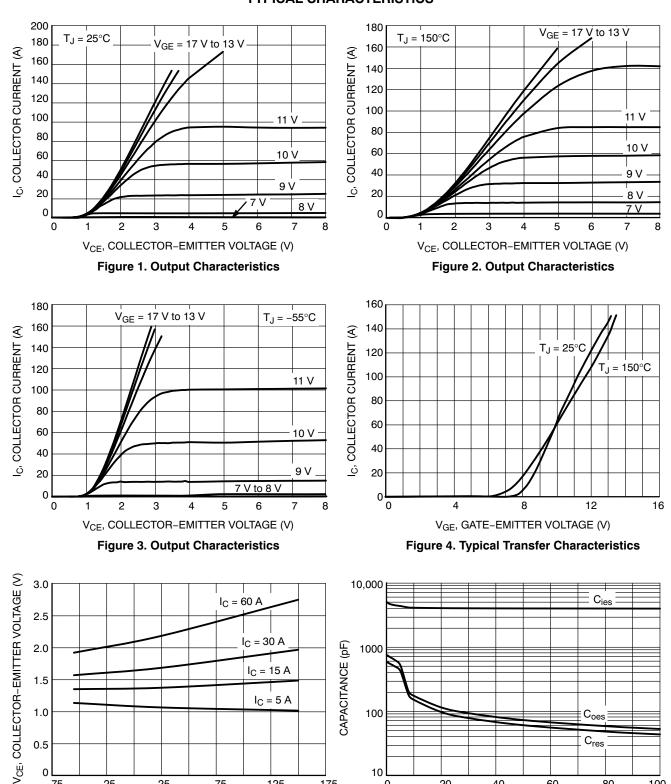
# THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.486	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	-				•	•
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V, I}_{C} = 500 \mu\text{A}$	V <sub>(BR)</sub> CES	600	-	-	V
Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A, T <sub>J</sub> = 150°C	V <sub>CEsat</sub>	1.4 -	1.65 2.0	1.9 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 200 \mu A$	V <sub>GE(th)</sub>	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V, T <sub>J</sub> = 150°C	I <sub>CES</sub>	1 1	_ _	0.2 2	mA
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V , V <sub>CE</sub> = 0 V	I <sub>GES</sub>	-	_	100	nA
DYNAMIC CHARACTERISTIC	•					
Input capacitance		C <sub>ies</sub>	-	4200	_	pF
Output capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>oes</sub>	-	130	_	
Reverse transfer capacitance	7	C <sub>res</sub>	-	110	-	.
Gate charge total		Qg	-	170	-	nC
Gate to emitter charge	V <sub>CE</sub> = 480 V, I <sub>C</sub> = 30 A, V <sub>GE</sub> = 15 V	Q <sub>ge</sub>	_	34	_	1
Gate to collector charge	7	Q <sub>gc</sub>	-	83	-	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD	•		•	•	
Turn-on delay time		t <sub>d(on)</sub>	-	83	_	ns
Rise time	7	t <sub>r</sub>	-	31	-	1
Turn-off delay time	_ Тյ = 25°C	t <sub>d(off)</sub>	-	170	_	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 30 \text{ A}$	t <sub>f</sub>	-	80	-	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 \text{ V} / 15 \text{ V}$	E <sub>on</sub>	-	0.7	-	mJ
Turn-off switching loss	7	E <sub>off</sub>	-	0.28	-	1
Total switching loss	7	E <sub>ts</sub>	-	0.98	-	
Turn-on delay time		t <sub>d(on)</sub>	-	81	-	ns
Rise time	7	t <sub>r</sub>	-	32	-	1
Turn-off delay time	T <sub>J</sub> = 150°C	t <sub>d(off)</sub>	-	180	-	1
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 30 \text{ A}$	t <sub>f</sub>	-	110	-	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 \text{ V} / 15 \text{ V}$	E <sub>on</sub>	-	0.82	-	mJ
Turn-off switching loss		E <sub>off</sub>	-	0.63	-	1
Total switching loss	1	E <sub>ts</sub>	-	1.45	_	1

#### TYPICAL CHARACTERISTICS



175

40

V<sub>CE</sub>, COLLECTOR-EMITTER VOLTAGE (V) Figure 6. Typical Capacitance

100

-75

T<sub>J</sub>, JUNCTION TEMPERATURE (°C)

Figure 5. V<sub>CE(sat)</sub> vs. T<sub>J</sub>

#### TYPICAL CHARACTERISTICS

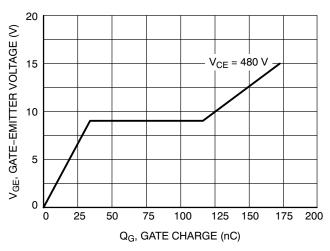


Figure 7. Typical Gate Charge

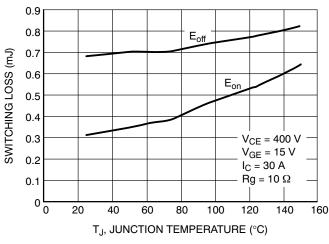


Figure 8. Switching Loss vs. Temperature

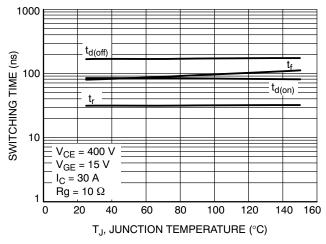


Figure 9. Switching Time vs. Temperature

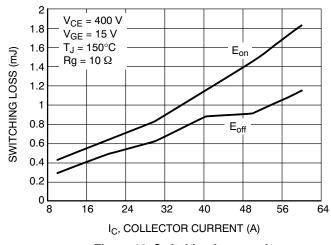


Figure 10. Switching Loss vs. I<sub>C</sub>

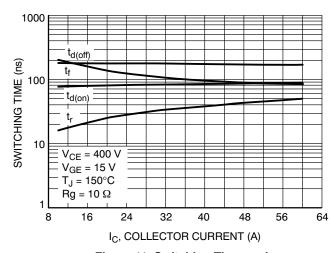
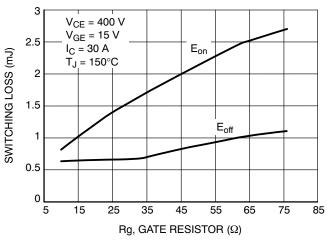


Figure 11. Switching Time vs.  $I_C$ 

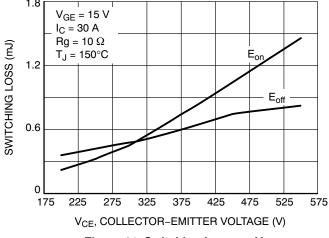
### TYPICAL CHARACTERISTICS



1000 t<sub>d(off)</sub> SWITCHING TIME (ns) 100  $t_{d(on)}$ 10 V<sub>CE</sub> = 400 V  $V_{GE} = 15 V$  $I_{C} = 30 \text{ A}$ T<sub>J</sub> = 150°C 15 25 35 45 65 Rg, GATE RESISTOR  $(\Omega)$ 

Figure 12. Switching Loss vs. Rg

Figure 13. Switching Time vs. Rg





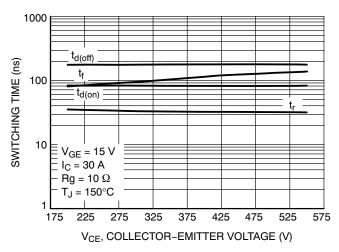


Figure 15. Switching Time vs. V<sub>CE</sub>

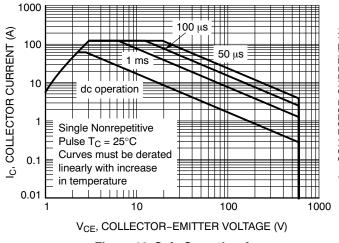


Figure 16. Safe Operating Area

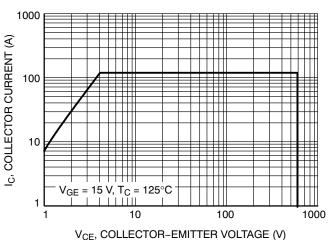


Figure 17. Reverse Bias Safe Operating Area

### **TYPICAL CHARACTERISTICS**

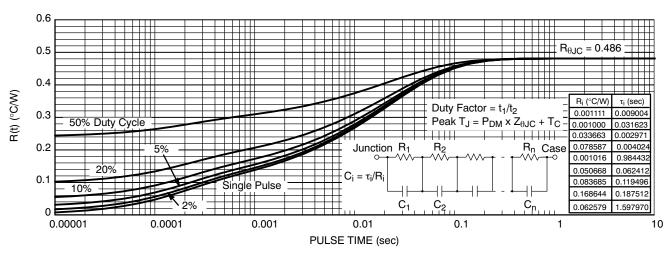


Figure 18. IGBT Transient Thermal Impedance

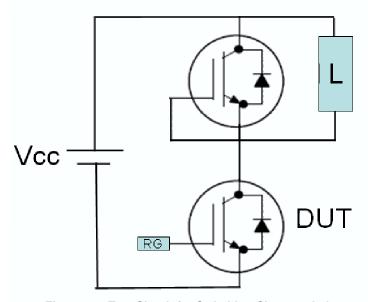


Figure 19. Test Circuit for Switching Characteristics

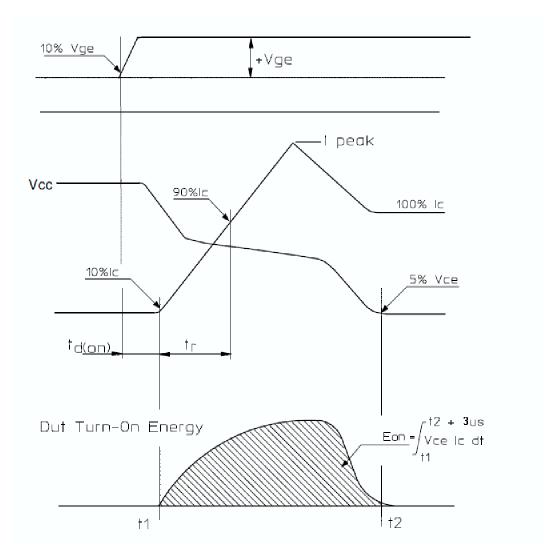


Figure 20. Definition of Turn On Waveform

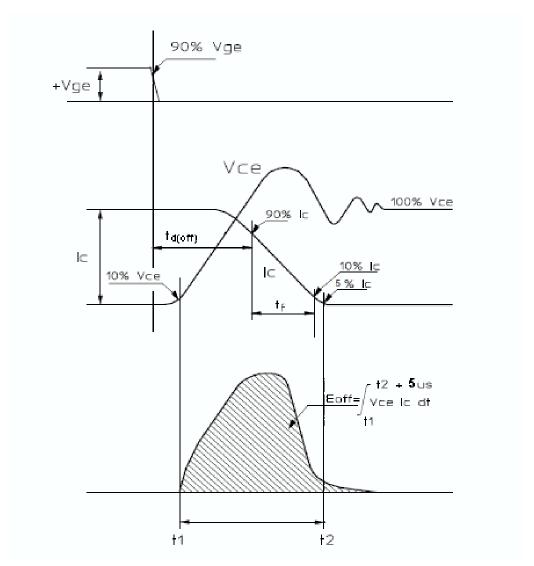
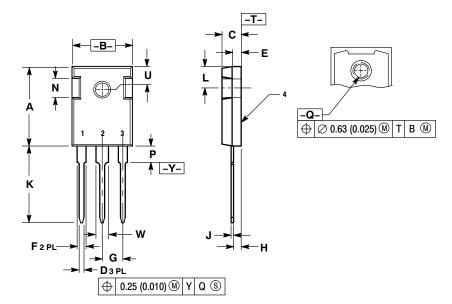


Figure 21. Definition of Turn Off Waveform

#### PACKAGE DIMENSIONS

TO-247 CASE 340L-02 ISSUE F



- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982
- 2. CONTROLLING DIMENSION: MILLIMETER.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	20.32	21.08	0.800	8.30	
В	15.75	16.26	0.620	0.640	
С	4.70	5.30	0.185	0.209	
D	1.00	1.40	0.040	0.055	
E	1.90	2.60	0.075	0.102	
F	1.65	2.13	0.065	0.084	
G	5.45 BSC		0.215 BSC		
Н	1.50	2.49	0.059	0.098	
J	0.40	0.80	0.016	0.031	
K	19.81	20.83	0.780	0.820	
L	5.40	6.20	0.212	0.244	
N	4.32	5.49	0.170	0.216	
P		4.50		0.177	
Q	3.55	3.65	0.140	0.144	
U	6.15	BSC	0.242 BSC		
w	2 87	3 12	0 113	0 123	

STYLE 4:

- PIN 1. GATE 2. COLLECTOR 3. EMITTER 4. COLLECTOR

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